| Total No. | of Questions | :8] |
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| SEAT No.: | |
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P768

[Total No. of Pages: 2

P.T.O.

[6005]-779

M.E. (E &TC) (VLSD & Embedded Systems) ASIC DESIGN (2017 Pattern) (Semester - III) (604202)

| Time | :3H | Jours] [Max. Marks | : 50 |
|-------------|------------|---|------|
| Instr | uctio | ns to the condidates: | |
| | 1) | Attempt any Five questions out of Eight. | |
| | <i>2</i>) | Near diagrams must be drawn whenever necessary. | |
| | <i>3</i>) | Figures to the right indicates full marks. | |
| | <i>4</i>) | Assume suitable data, if necessary. | |
| Q 1) | a) | Write short note on logic level optimization. | [5] |
| | b) | Draw and explain ASIC Design Flow. | [5] |
| Q 2) | Expl | lain the terms | [5] |
| | i) | Constants | |
| | ii) | Variable | |
| | iii) | Attributes | ; ¿; |
| | b) | Write VHDL code and test-bench code for 4-bit shift register. | [5] |
| <i>Q3</i>) | a) | Write short note on power Dissipation | [4] |
| | b) | Explain in brief system partitioning technique in ASIC. | [4] |
| | c) | Write CAD tools used in ASIC Design. | [2] |
| Q4) | a) | Explain in detail floor planning in ASIC with one example. | [4] |
| | b) | Write short note on routing techiniques in ASIC. | [4] |
| | c) | What are the goals and objectives of placement. | [2] |
| | | | |

| Q5) | a) | Explain power optimization techniques in ASIC. | [4] |
|-------------|---------------|--|-----|
| | b) | With one example describe time optimization technique. | [4] |
| | c) | How to estimate delays in ASIC Design. | [2] |
| Q6) | a) | Explain in detail different time constraints in ASIC Design. | [4] |
| | b) | Write short note on static timing analysis. | [4] |
| | c) | How to design ASIC library. Comment on uses of library. | [2] |
| Q7) | a) | Describe with one example gate level mixed mode simulation. | [4] |
| | b) | Write short note on scan and partial test. | [4] |
| | c) | Explain design challenges in mixed signal ASIC Design. | [2] |
| Q8) | a) N | Describe in brief Automatic Test pattern Generator. | [4] |
| | b) | Write short note on memory testing. | [4] |
| | c) | What is the signal integrity issues occured in ASIC Design. | [2] |
| | | And the state of t | |
| [600 |) 5]-7 | 2 | |